

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10530861	FUKUSHIMA ET AL.
	<b>Examiner</b> Nguyen, Lauren	<b>Art Unit</b> 2871

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
349	15, 201-202	04/03/2007	LN
359	376, 462	04/03/2007	LN

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted Primary Examiner Andrew Schechter	04/03/2007	LN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>